



December 1993
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74F1056 8-Bit Schottky Barrier Diode Array

General Description

The 74F1056 is an 8-bit Schottky barrier diode array designed to be employed as termination on the inputs to memory bus lines or CLOCK lines. This device is designed to suppress negative transients caused by line reflections, switching noise and crosstalk.

Features

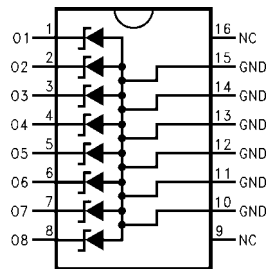
- 8-Bit array structure designed to suppress negative transients
- Guaranteed ESD protection (HBM) in excess of 4 kV
- Common anode shared by all eight diodes
- Broadside pinout for ease of bus routing

Ordering Code:

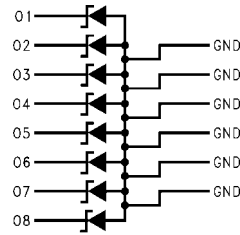
Order Number	Package Number	Package Description
74F1056SC	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150 Narrow

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Connection Diagram



Schematic Diagram



74F1056 8-Bit Schottky Barrier Diode Array

74F1056

Absolute Maximum Ratings (Note 1)

Storage Temperature	-65°C to +150°C
Operating Free-Air Temperature	0°C to 70°C
Steady State Reverse Voltage, (V _R)	7.0V
Continuous Total Power Dissipation at or below 25°C Free-Air Temperature, (P _D)	750 mW
Continuous Forward Current, (I _F)	
Any Output Pin to GND	50 mA
Total Through All GND Pins	170 mA
Repetitive Peak Forward Current, I _{FP} (Note 2)	
Any Output Pin to GND	300 mA
Total Through All GND Pins	1.2A
ESD (HBM)	4 kV

Note 1: Absolute maximum ratings are valued beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: These values apply for the t_w ≤ 100 μs, duty cycle ≤ 20%.

DC Electrical Characteristics

Over recommended operating free air temperature range, unless otherwise noted

SINGLE DIODE OPERATION (Note 3)

Symbol	Parameter	Min	Typ	Max	Units	Conditions
V _{BR}	Reverse Breakdown Voltage	7.0			V	I _R = 10 μA
I _R	Static Reverse Current			10	μA	V _R = 7V
V _F	Static Forward Voltage		-0.65 -0.8	-0.85 -1.0	V	I _F = -16 mA I _F = -50 mA
C _T	Total Capacitance		5 4	10 8	pF	V _I = 0V, f = 1 MHz V _I = 2V, f = 1 MHz

Note 3: These tests apply to separate diode operation, diodes not under test are open-circuit.

MULTIPLE DIODE OPERATION

Symbol	Parameter	Min	Typ	Max	Units	Conditions
I _{CR}	Internal Crosstalk Current		0.2	2	mA	Total GND current = 1.2A (Note 4)

Note 4: I_{CR} is measured under the following conditions: One diode static, all others switching

Switching diodes: t_w = 100 μs; Static diode: V_{IN} = 6V

Duty cycle = 20%, I_F = 200 mA

The static diode input current is the internal crosstalk current I_{CR}.

AC Electrical Characteristics

T_A = 25°C

Symbol	Parameter	Min	Typ	Max	Units	Conditions	Figure Number
V _{FR}	Forward Recovery Voltage		1.25		V	I _F = 300 mA	Figure 1
T _{RR}	Reverse Recovery Time			5.0	ns	I _F = 10 mA, I _R = 1 mA R _L = 100Ω	Figure 2

AC Loading and Waveforms

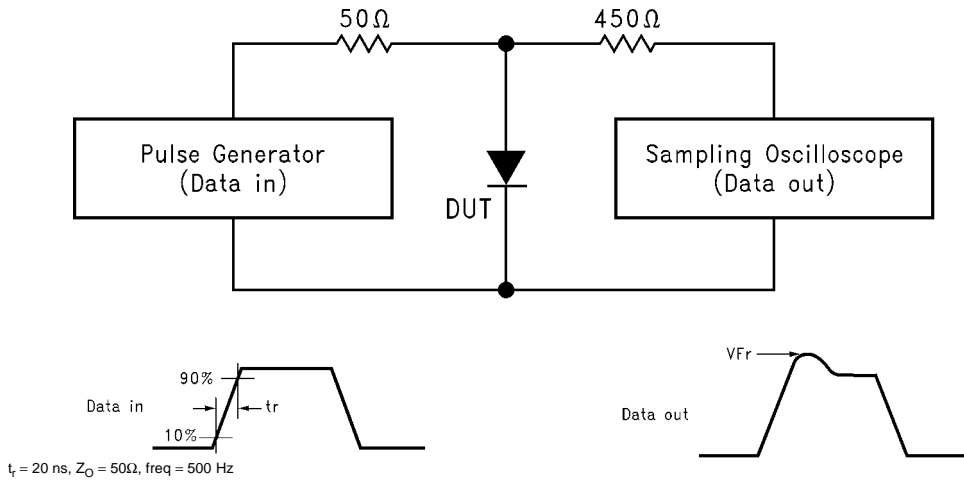


FIGURE 1. Forward Recovery Voltage

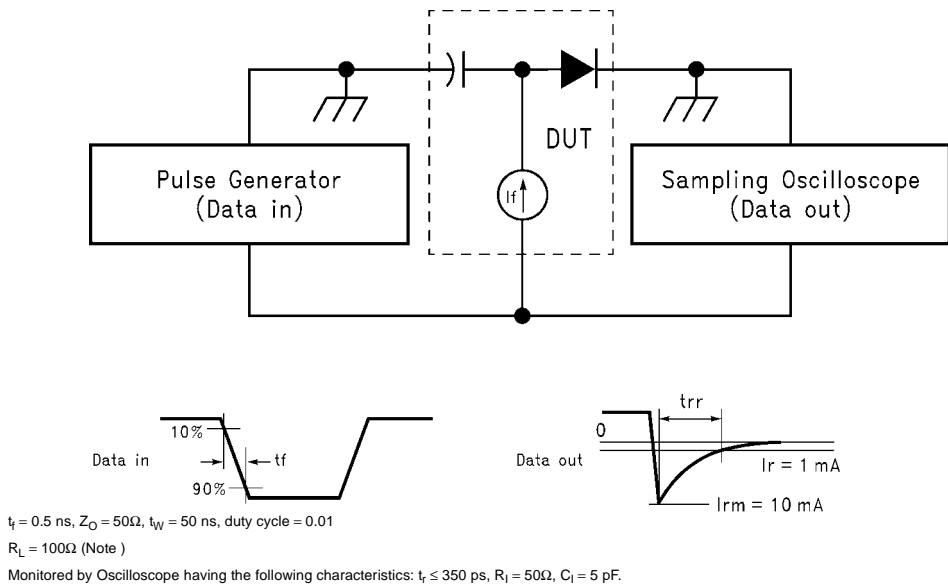
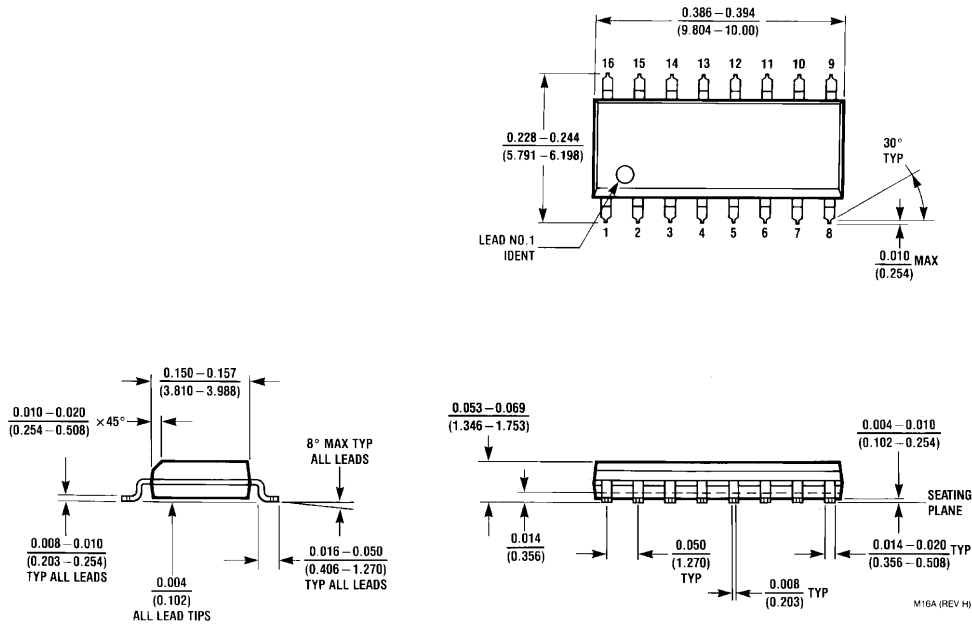


FIGURE 2. Reverse Recovery Time

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Physical Dimensions inches (millimeters) unless otherwise noted



16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150 Narrow Package Number M16A

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